# Notice of References Cited

Application/Control No.	Applicant(s)/Pate	nt Under
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Examiner	Art Unit	
Zeev Kitov	2836	Page 1 of 1

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.